

Portable Equipment Application.

Notebook Application.

Features

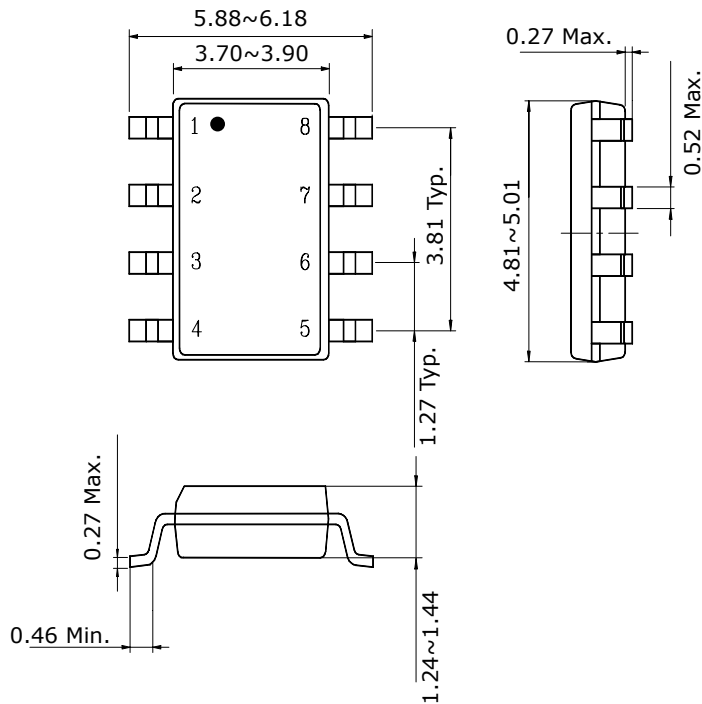
- Low $V_{GS(th)}$: $V_{GS(th)}=1.0\sim3.0V$
- Small footprint due to small package
- Low $R_{DS(ON)}$: Low $R_{DS(ON)}=N\text{-ch}:24m\Omega$, $P\text{-ch}:66m\Omega$

Ordering Information

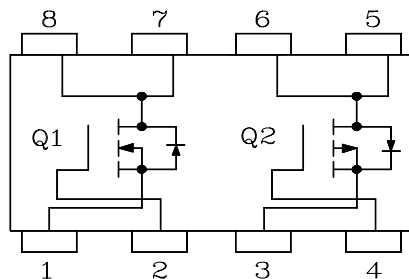
Type NO.	Marking	Package Code
SUF2001	SUF2001	SOP-8

Outline Dimensions

unit : mm



Block Diagram



PIN Connections

1. Source 1
2. Gate 1
3. Source 2
4. Gate 2
5. Drain 2
6. Drain 2
7. Drain 1
8. Drain 1

Absolute maximum ratings

(Ta=25°C)

Characteristic	Symbol	Rating		Unit
		N-Ch	P-Ch	
Drain-source voltage	V_{DSS}	30	-30	V
Gate-source voltage	V_{GSS}	±20		V
Drain current (DC)	I_D	5.8	-5.3	A
Drain current (Pulsed) *	I_{DP}	23.2	-21.2	A
Total Power dissipation **	P_D	2.0		W
Avalanche current (Single)	I_{AS}	②5.8	⑥-5.3	A
Single pulsed avalanche energy	E_{AS}	②72	⑥33	mJ
Avalanche current (Repetitive) ①	I_{AR}	5.8	-5.3	A
Repetitive avalanche energy ①	E_{AR}	3.4	1.6	mJ
Junction temperature	T_J	150		°C
Storage temperature range	T_{stg}	-55~150		

* Limited by maximum junction temperature

** Device mounted on a glass-epoxy board

Characteristic		Symbol	Typ.	Max	Unit
Thermal resistance	Junction-ambient	$R_{th(J-a)}$	62.5	-	°C/W

N-CH Electrical Characteristics

(Ta=25°C)

Characteristic	Symbol	Test Condition	Min.	Typ.	Max.	Unit	
Drain-source breakdown voltage	BV_{DSS}	$I_D=250\mu A, V_{GS}=0$	30	-	-	V	
Gate threshold voltage	$V_{GS(th)}$	$I_D=250\mu A, V_{DS}=V_{GS}$	1.0	-	3.0	V	
Drain-source cut-off current	I_{DSS}	$V_{DS}=30V, V_{GS}=0V$	-	-	1	μA	
Gate leakage current	I_{GSS}	$V_{DS}=0V, V_{GS}=\pm 20V$	-	-	± 100	nA	
Drain-source on-resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=2.9A$	-	24	30	$m\Omega$	
		$V_{GS}=5.0V, I_D=2.9A$	-	28	34	$m\Omega$	
Forward transfer conductance ④	g_{fs}	$V_{DS}=5V, I_D=5.8A$	-	12	-	S	
Input capacitance	C_{iss}	$V_{GS}=0V, V_{DD}=10V,$ $f=1MHz$	-	370	560	pF	
Output capacitance	C_{oss}		-	60	90		
Reverse transfer capacitance	C_{rss}		-	36	54		
Turn-on delay time	$t_{d(on)}$	$V_{DD}=15V, I_D=5.8A$ $R_G=10\Omega$	-	1.2	-	ns	
Rise time	t_r		-	1.1	-		
Turn-off delay time	$t_{d(off)}$		③④	-	2.5		-
Fall time	t_f		-	1.1	-		
Total gate charge	Q_g	$V_{DD}=15V, V_{GS}=5V$ $I_D=5.8A$	-	4.2	6.3	nC	
Gate-source charge	Q_{gs}		③④	-	0.9		1.4
Gate-drain charge	Q_{gd}		-	-	1.4		2.1

Source-Drain Diode Ratings and Characteristics

(Ta=25°C)

Characteristic	Symbol	Test Condition	Min	Typ	Max	Unit
Source current	I_S	Integral reverse diode in the MOSFET	-	-	1.5	A
Source current(Pulsed) ①	I_{SM}		-	-	6.0	
Forward voltage ④	V_{SD}	$V_{GS}=0V, I_S=1.5A$	-	-	1.2	V
Reverse recovery time	t_{rr}	$I_S=1.5A$ $di_S/dt=100A/us$	-	90	-	ns
Reverse recovery charge	Q_{rr}		-	0.5	-	μC

Note ;

- ① Repetitive Rating : Pulse width limited by maximum junction temperature
- ② $L=3.4mH, I_{AS}=5.8A, V_{DD}=15V, R_G=25\Omega$
- ③ Pulse Test : Pulse Width < 300us, Duty cycle $\leq 2\%$
- ④ Essentially independent of operating temperature

P-CH Electrical Characteristics

(Ta=25°C)

Characteristic	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Drain-source breakdown voltage	BV_{DSS}	$I_D=250\mu A, V_{GS}=0$	-30	-	-	V
Gate threshold voltage	$V_{GS(th)}$	$I_D=250\mu A, V_{DS}=V_{GS}$	-1.0	-	-3.0	V
Drain-source cut-off current	I_{DSS}	$V_{DS}=-30V, V_{GS}=0V$	-	-	1	μA
Gate leakage current	I_{GSS}	$V_{DS}=0V, V_{GS}=\pm 20V$	-	-	± 100	nA
Drain-source on-resistance	$R_{DS(on)}$	$V_{GS}=-10V, I_D=-2.7A$	-	66	72	$m\Omega$
		$V_{GS}=-5.0V, I_D=-2.7A$	-	77	83	$m\Omega$
Forward transfer conductance ⑧	g_{fs}	$V_{DS}=-5V, I_D=-5.3A$	-	11	-	S
Input capacitance	C_{iss}	$V_{GS}=0V, V_{DD}=-10V, f=1MHz$	-	390	590	pF
Output capacitance	C_{oss}		-	97	150	
Reverse transfer capacitance	C_{rss}		-	37	60	
Turn-on delay time	$t_{d(on)}$	$V_{DD}=-15V, I_D=-5.3A, R_G=10\Omega$ ⑦⑧	-	1.2	-	ns
Rise time	t_r		-	1.1	-	
Turn-off delay time	$t_{d(off)}$		-	2.5	-	
Fall time	t_f		-	1.1	-	
Total gate charge	Q_g	$V_{DD}=-15V, V_{GS}=-5V, I_D=-5.3A$ ⑦⑧	-	4.7	7.0	nC
Gate-source charge	Q_{gs}		-	1.4	2.1	
Gate-drain charge	Q_{gd}		-	1.7	2.5	

Source-Drain Diode Ratings and Characteristics

(Ta=25°C)

Characteristic	Symbol	Test Condition	Min	Typ	Max	Unit
Source current	I_S	Integral reverse diode in the MOSFET	-	-	-1.5	A
Source current(Pulsed) ⑤	I_{SM}		-	-	-6.0	
Forward voltage ⑧	V_{SD}	$V_{GS}=0V, I_S=-1.5A$	-	-	-1.2	V
Reverse recovery time	t_{rr}	$I_S=-1.5A, di_S/dt=100A/us$	-	90	-	ns
Reverse recovery charge	Q_{rr}		-	0.5	-	μC

Note ;

- ⑤ Repetitive Rating : Pulse Width Limited by Maximum Junction Temperature
- ⑥ $L=2.0mH, I_{AS}=-5.0A, V_{DD}=-15V, R_G=25\Omega$
- ⑦ Pulse Test : Pulse Width < 300us, Duty cycle $\leq 2\%$
- ⑧ Essentially independent of operating temperature

N-CH Electrical Characteristic Curves

Fig. 1 $I_D - V_{DS}$

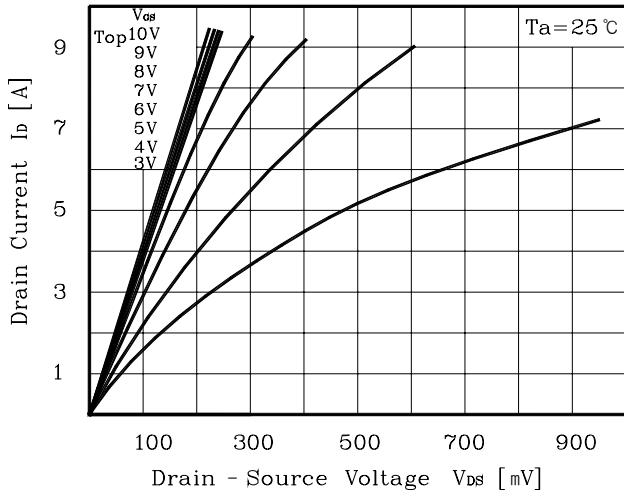


Fig. 2 $I_D - V_{GS}$

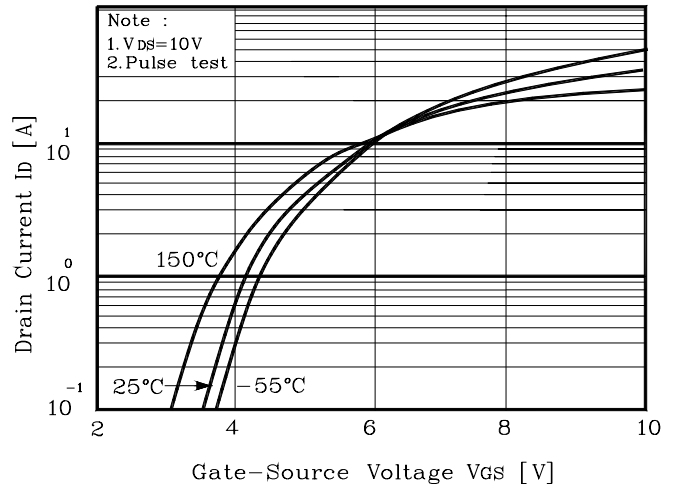


Fig. 3 $R_{DS(on)} - I_D$

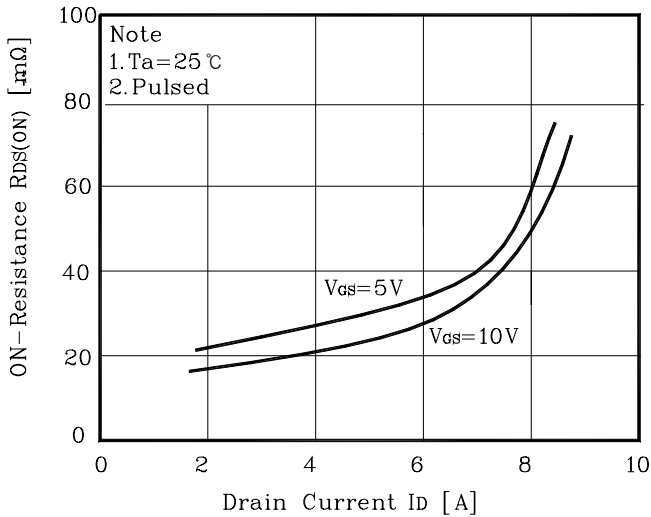


Fig. 4 $I_S - V_{SD}$

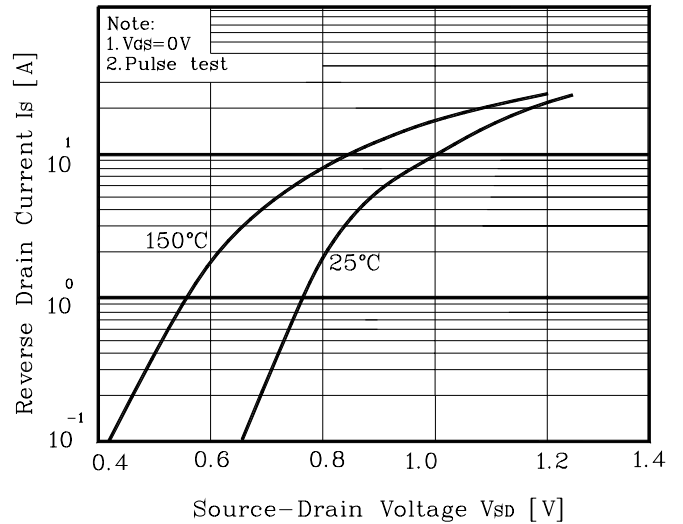


Fig. 5 Capacitance - V_{DS}

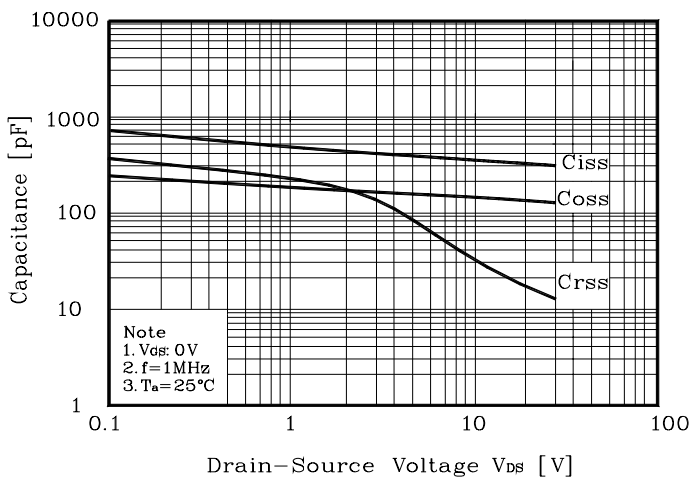


Fig. 6 $V_{GS} - Q_G$

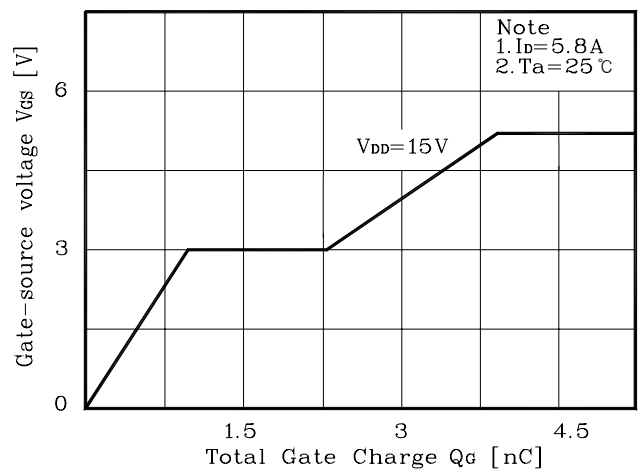


Fig. 7 $V_{DSS} - T_J$

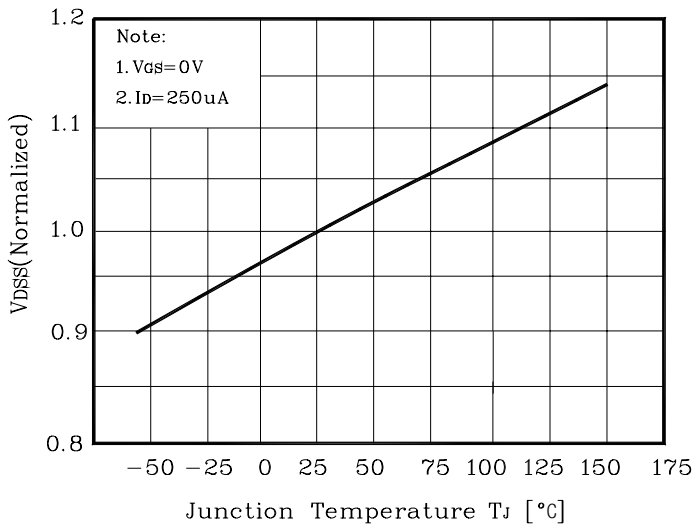


Fig. 8 $R_{DS(on)} - T_J$

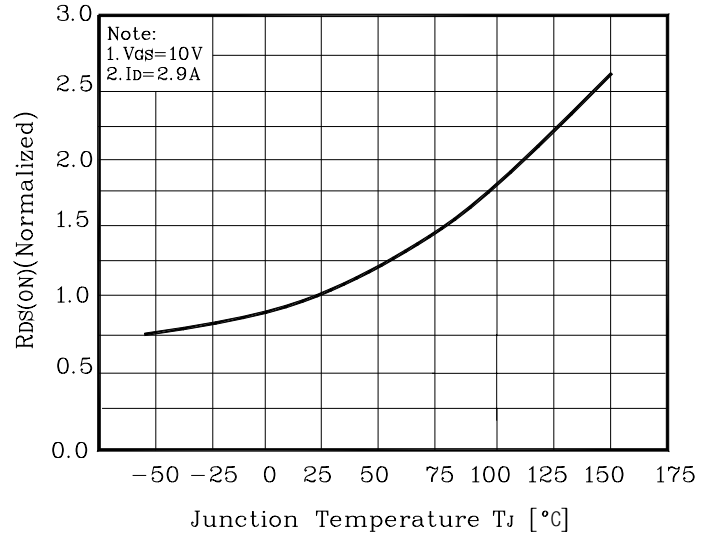


Fig. 9 $I_D - T_a$

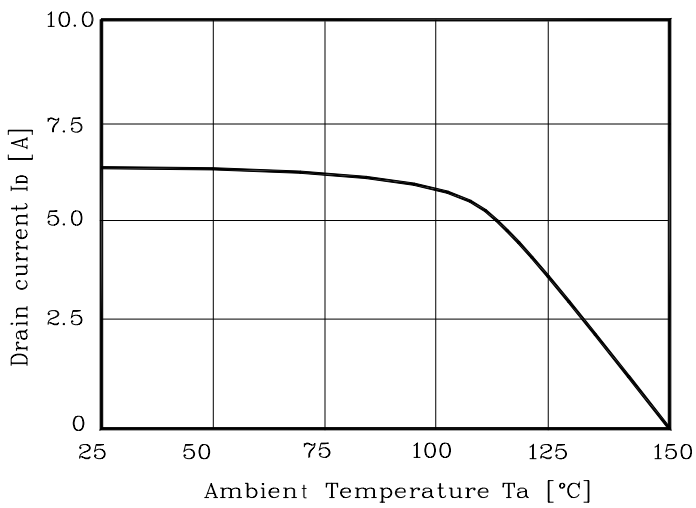


Fig. 10 Safe Operating Area

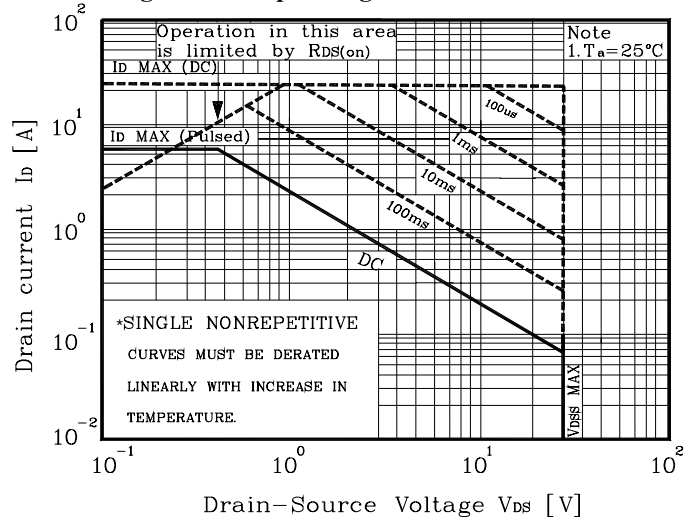


Fig. 11 Gate Charge Test Circuit & Waveform

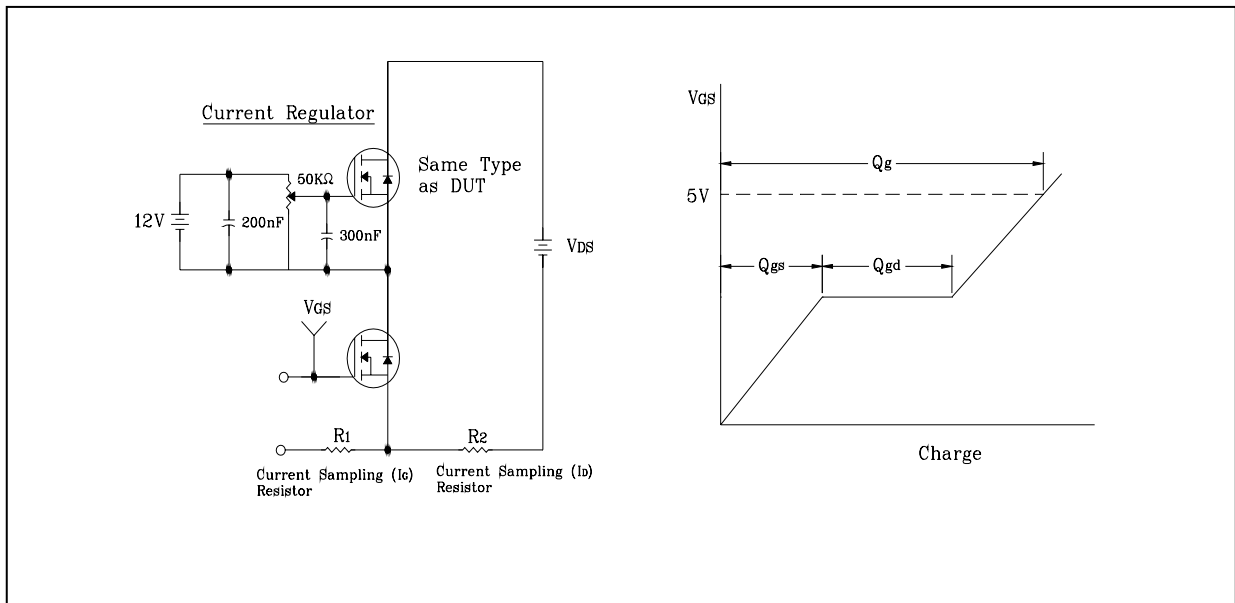


Fig. 12 Resistive Switching Test Circuit & Waveform

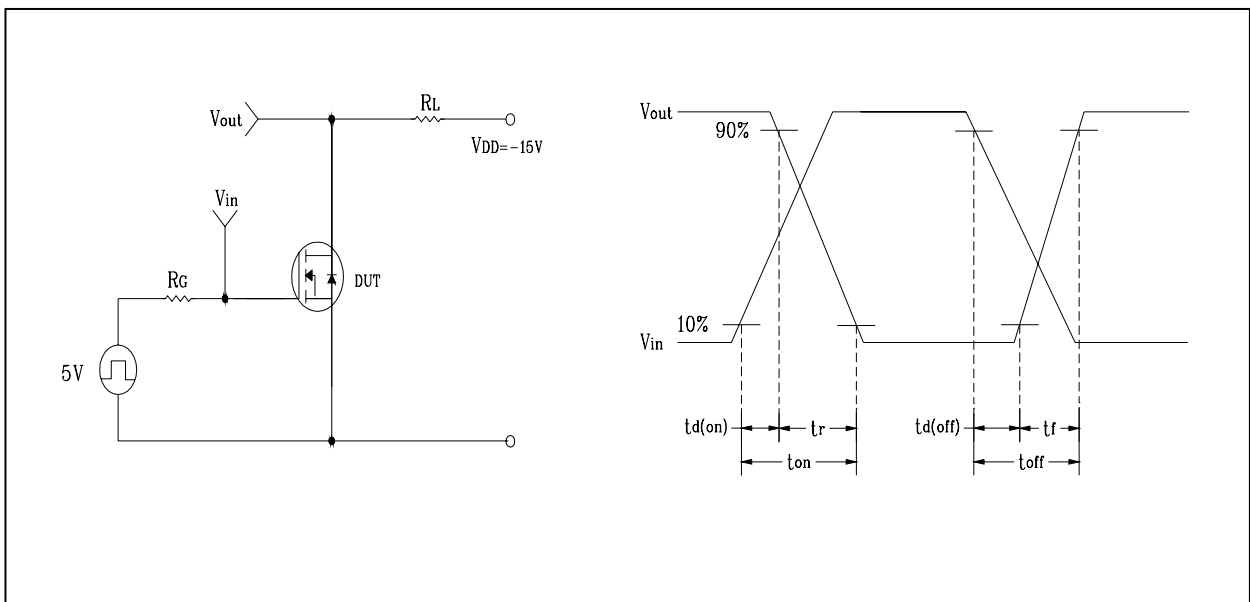


Fig. 13 E_{AS} Test Circuit & Waveform

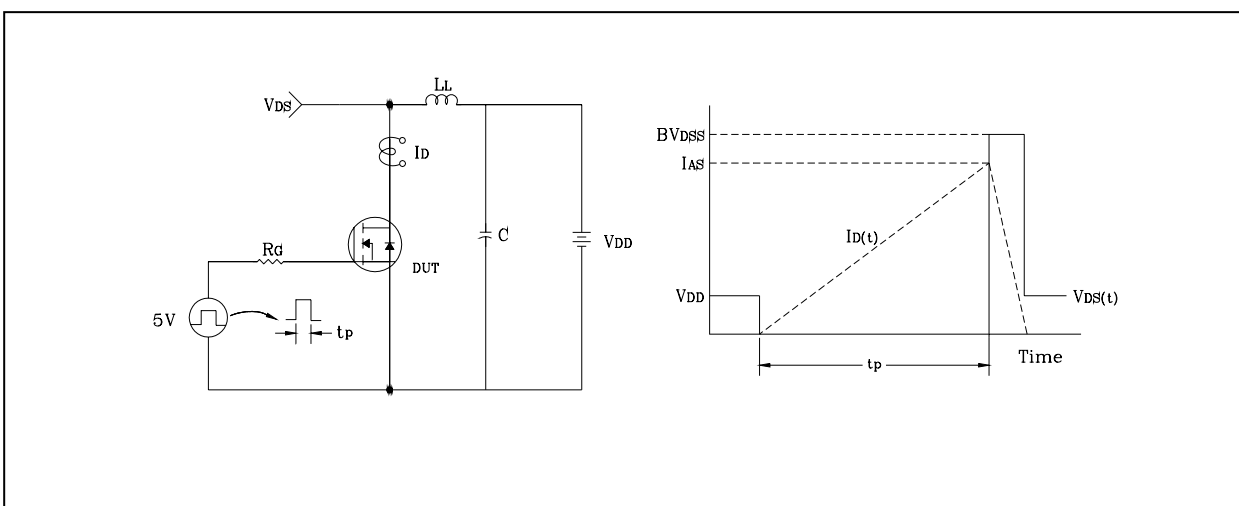
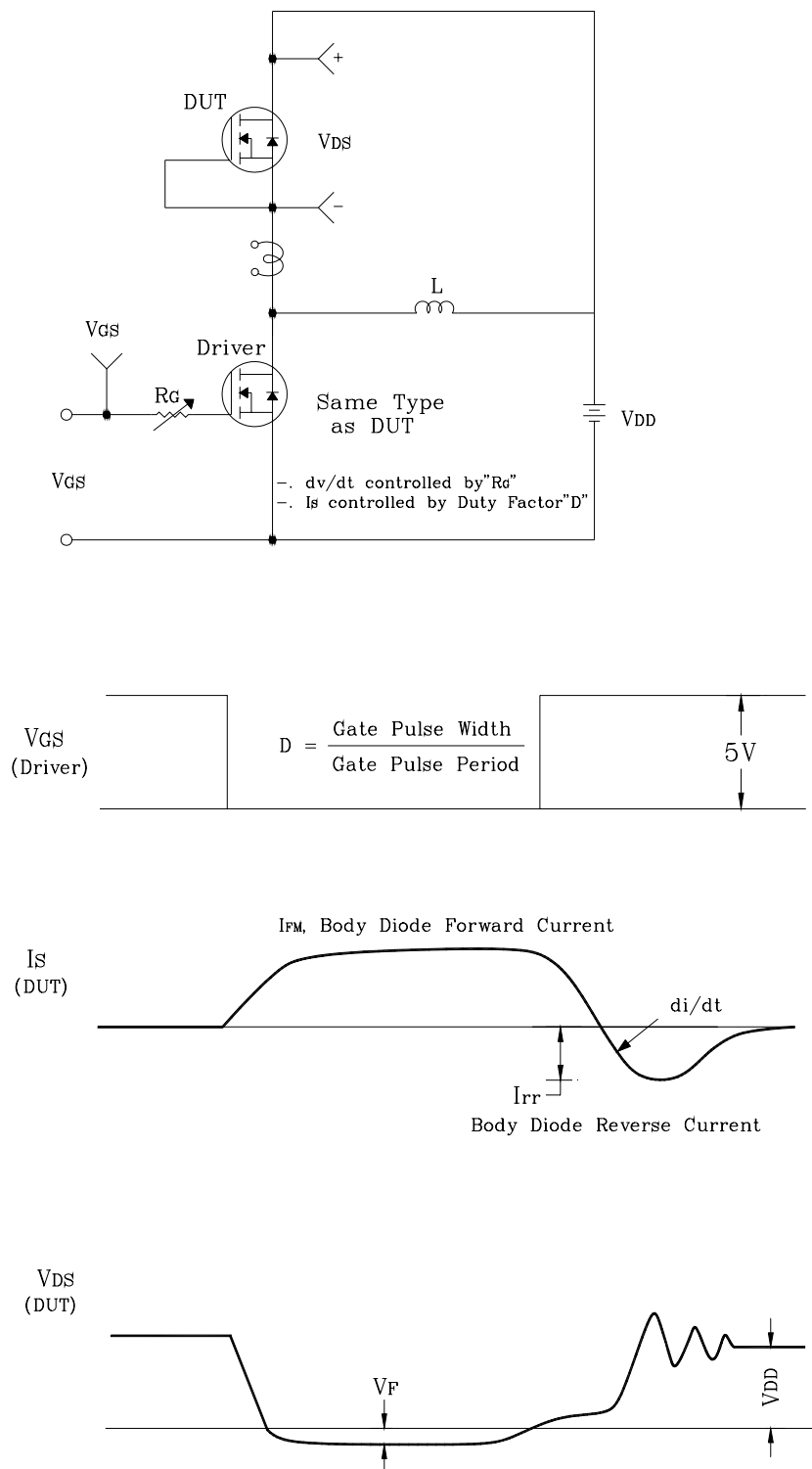


Fig. 14 Diode Reverse Recovery Time Test Circuit & Waveform



P-CH Electrical Characteristic Curves

Fig. 1 $I_D - V_{DS}$

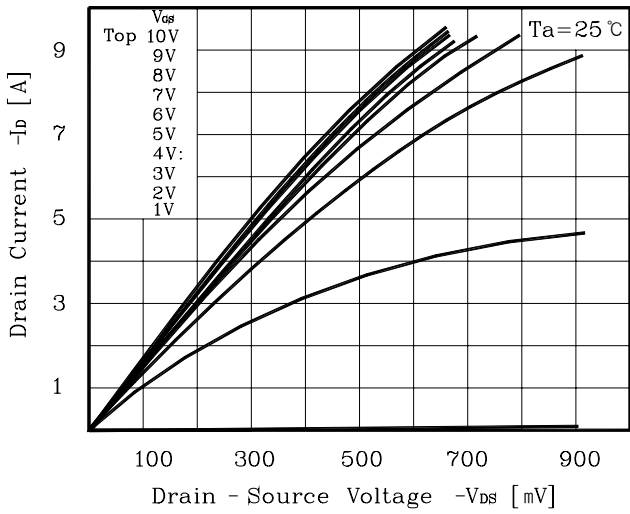


Fig. 2 $I_D - V_{GS}$

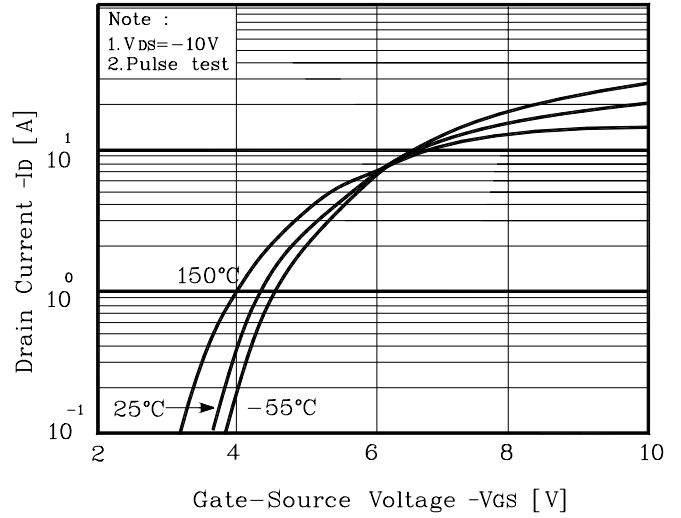


Fig. 3 $R_{DS(on)} - I_D$

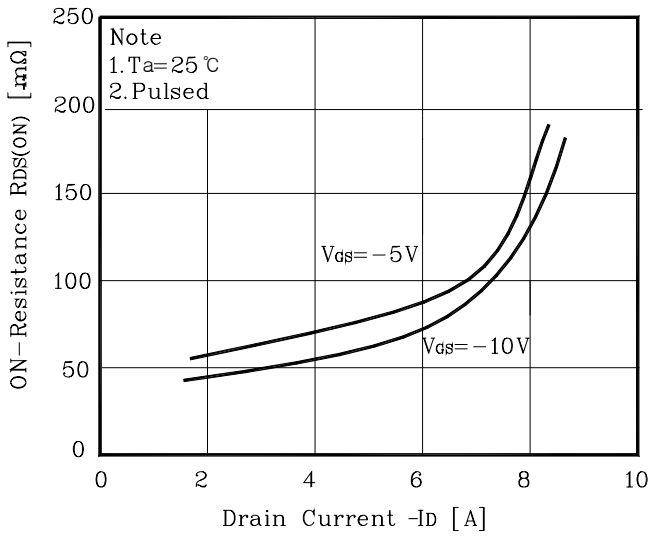


Fig. 4 $I_S - V_{SD}$

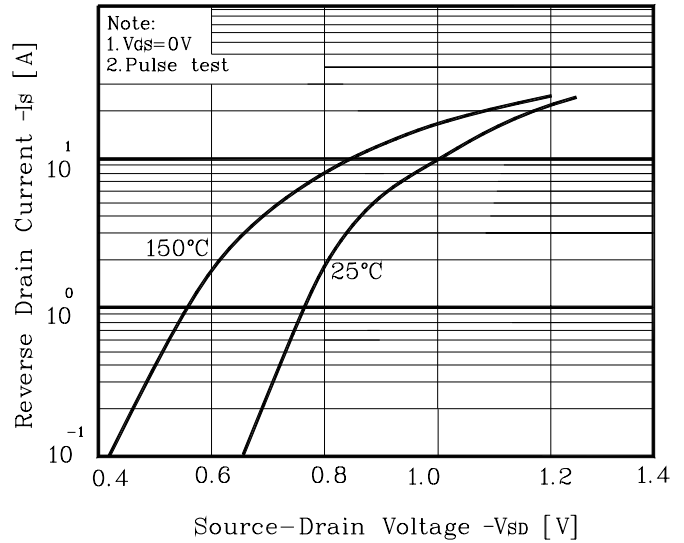


Fig. 5 Capacitance - V_{DS}

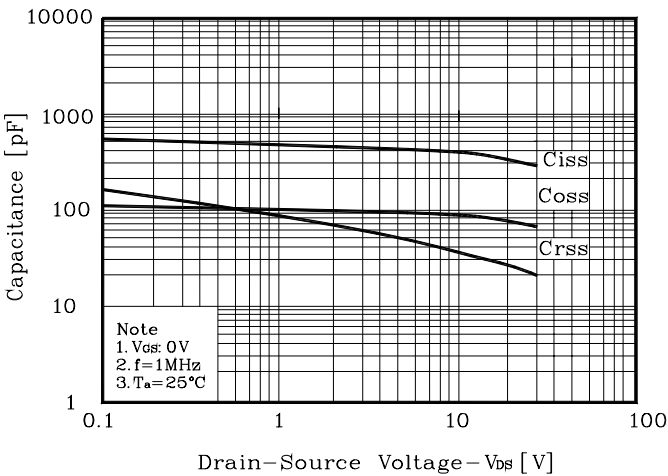


Fig. 6 $V_{GS} - Q_G$

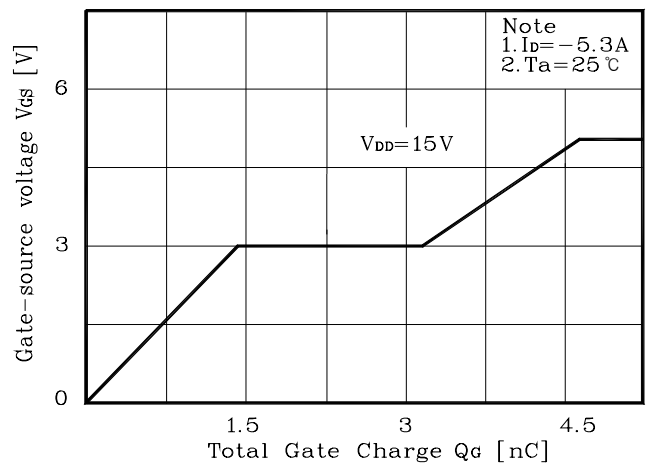


Fig. 7 $V_{DSS} - T_J$

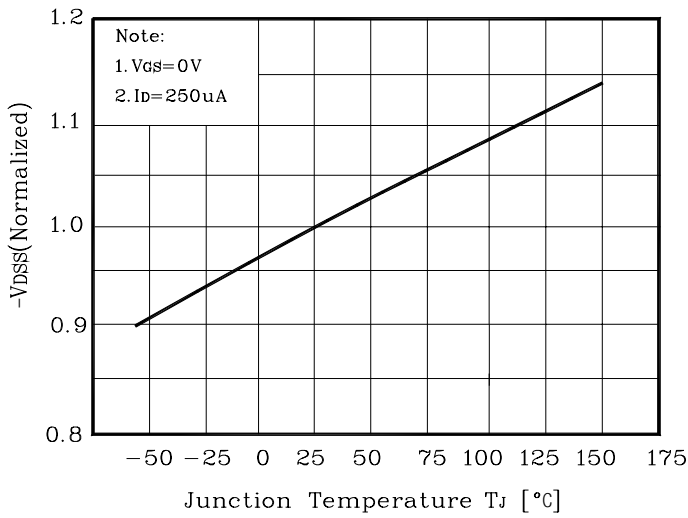


Fig. 8 $R_{DS(on)} - T_J$

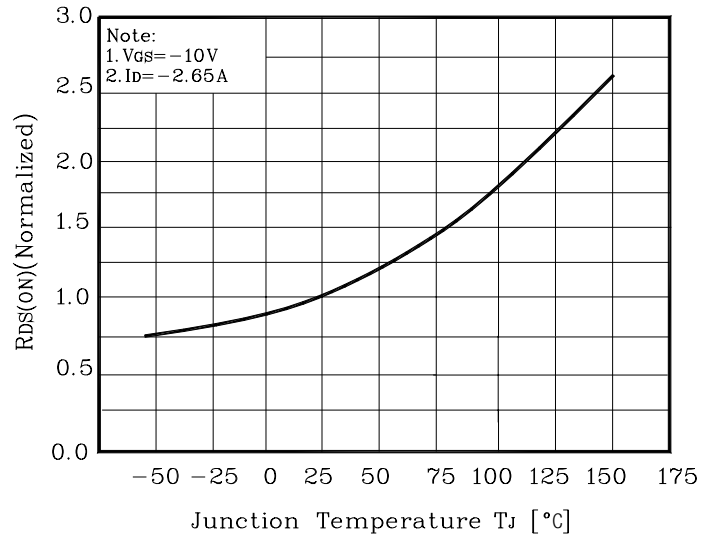


Fig. 9 $I_D - T_a$

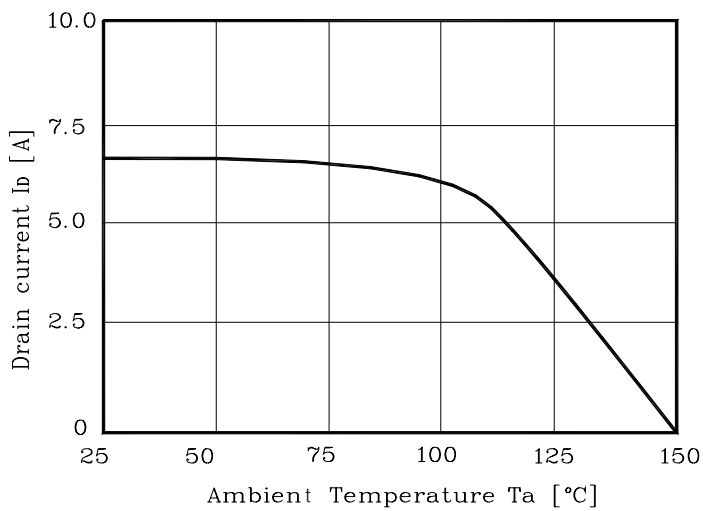


Fig. 10 Safe Operating Area

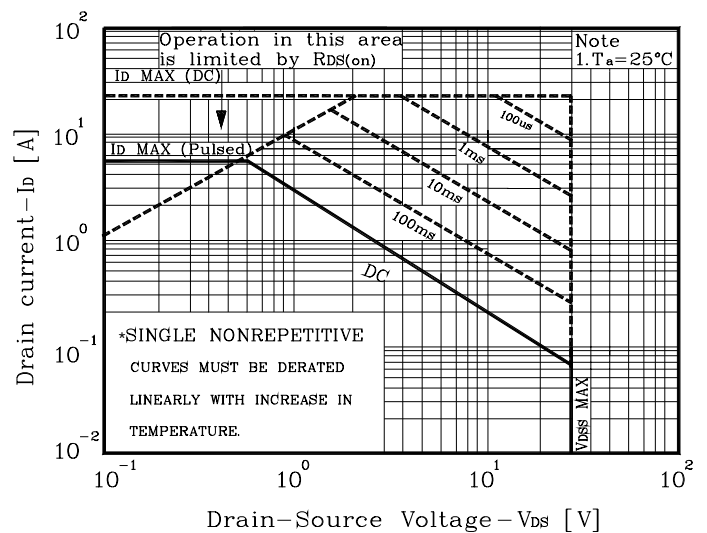


Fig. 11 Gate Charge Test Circuit & Waveform

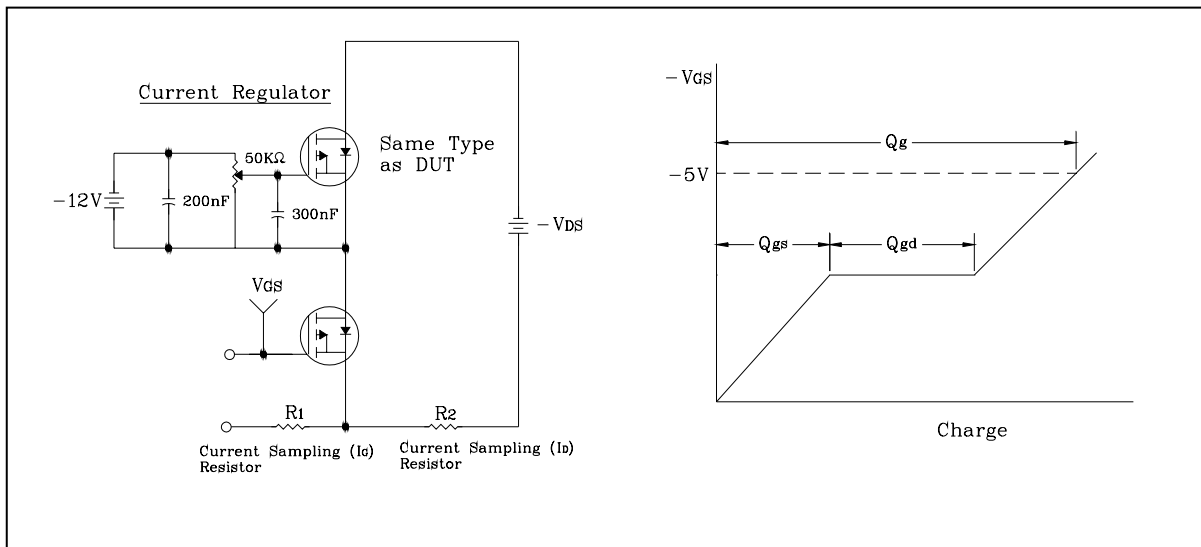


Fig. 12 Resistive Switching Test Circuit & Waveform

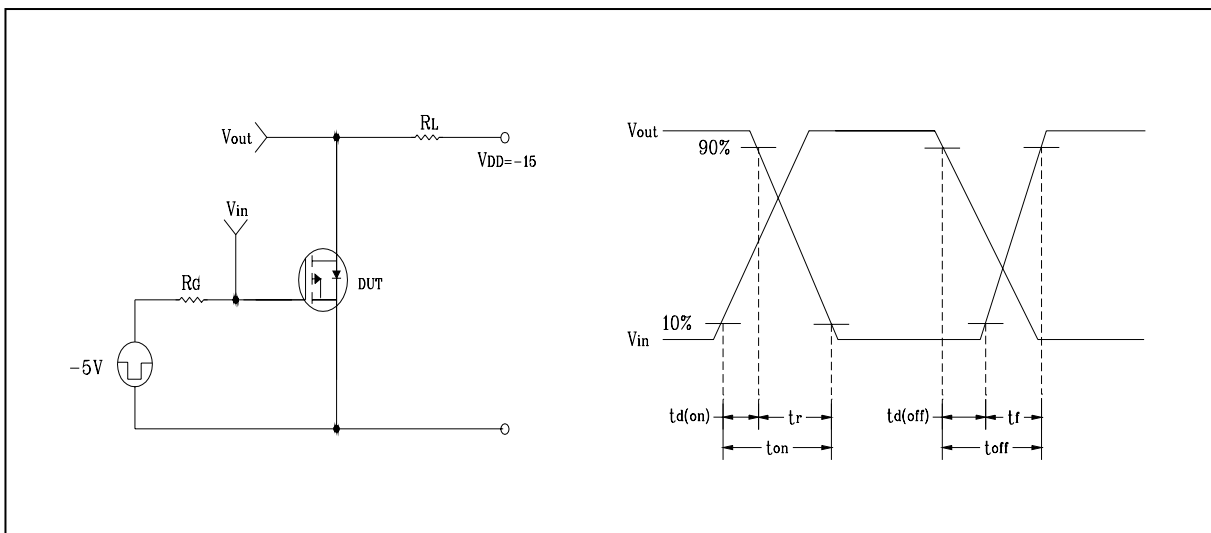


Fig. 13 E_{AS} Test Circuit & Waveform

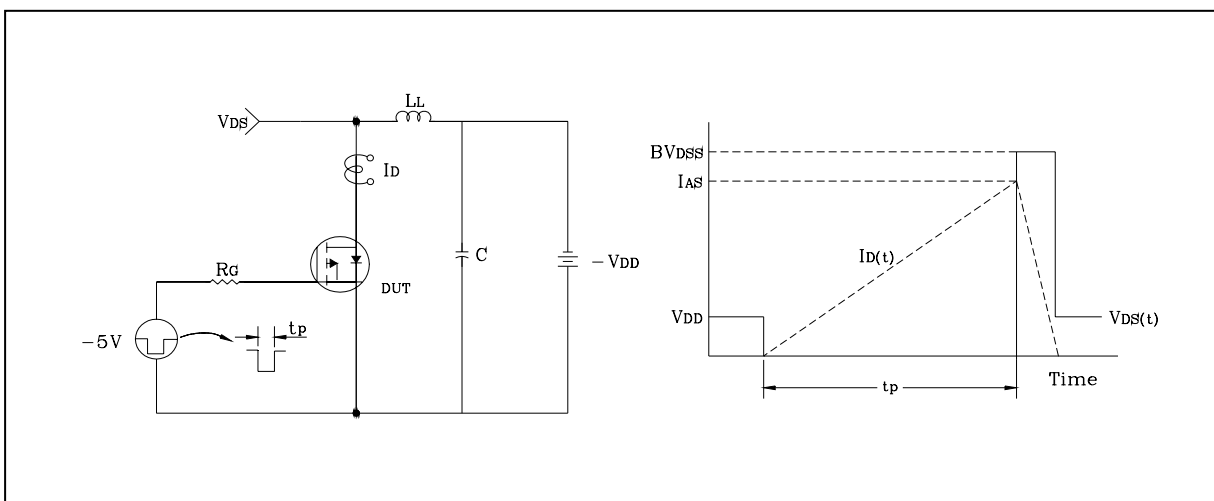
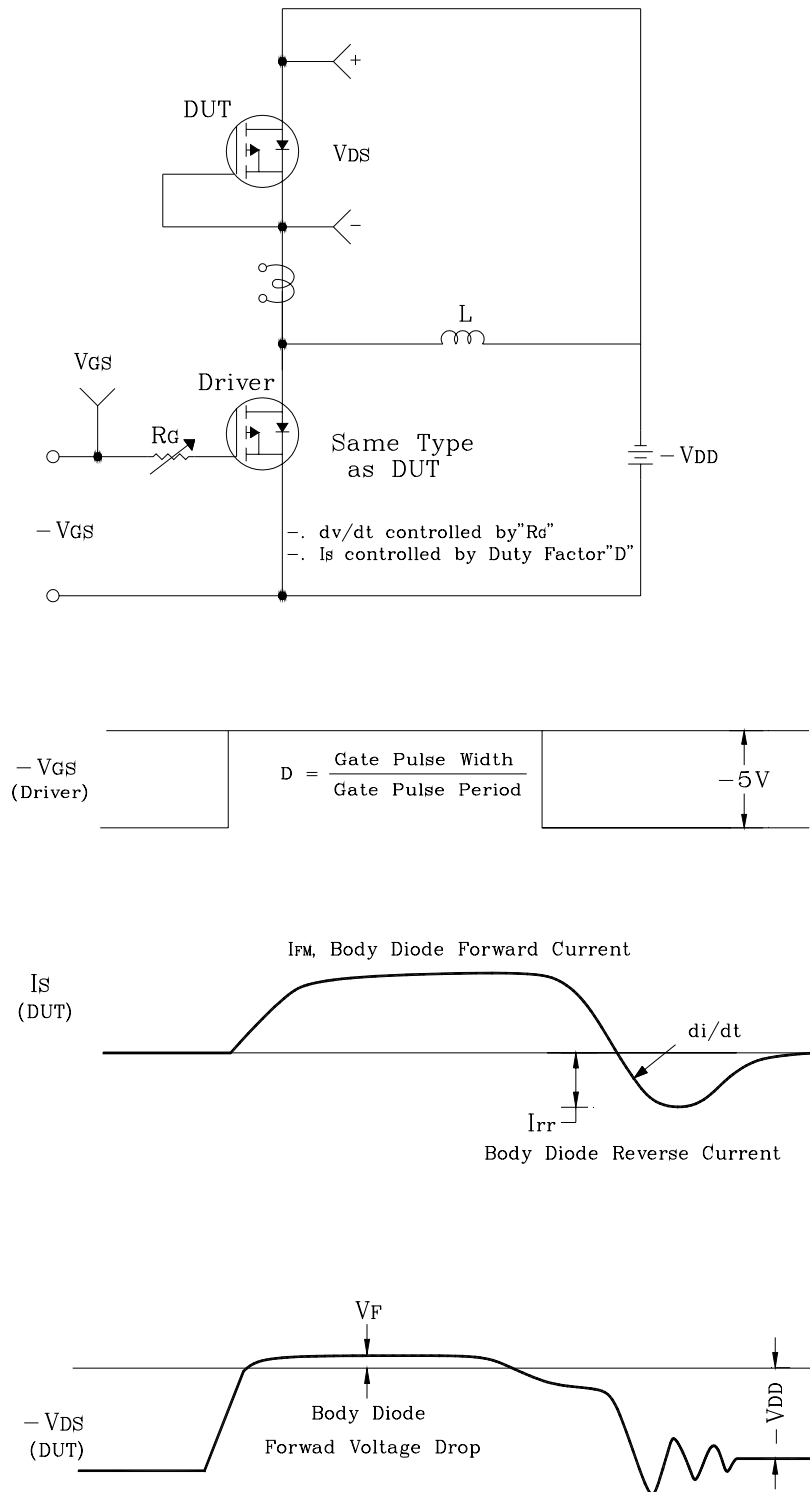


Fig. 14 Diode Reverse Recovery Time Test Circuit & Waveform



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